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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete If Known			
		Application Number	10/722,589		
		Filing Date	November 25, 2003		
		First Named Inventor	Ehud Cohen		
		Art Unit	3766		
		Examiner Name	M. Bockelman		
Sheet	1	of	2	Attorney Docket Number	06727/100J782-US5

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MS	BA	EP 0831954		04/1998			

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Examiner Signature	<i>M. Bockelman</i>	Date Considered	12-22-06
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